## Application/Control No. Applicant(s)/Patent Under Reexamination 10/814,198 YOON ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2621 Michael P. Choi **U.S. PATENT DOCUMENTS** Date Document Number Classification Name Country Code-Number-Kind Code MM-YYYY 348/565 US-2002/0057372 05-2002 Cavallerano et al. Α NORSWORTHY et al. 348/565 US-2003/0016304 A1 01-2003 В 386/46 US-2003/0099457 05-2003 Takahashi et al. С US-D US-Ε US-F US-G

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